

3.3 V, Crystal to 25 MHz, 100 MHz, 125 MHz and 200 MHz Dual HCSL Clock Generator

NB3N5573

Description

The NB3N5573 is a precision, low phase noise clock generator that supports PCI Express and Ethernet requirements. The device accepts a 25 MHz fundamental mode parallel resonant crystal and generates a differential HCSL output at 25 MHz, 100 MHz, 125 MHz or 200 MHz clock frequencies. Outputs can interface with LVDS with proper termination (See Figure 4).

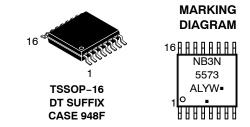
This device is housed in 5.0 mm x 4.4 mm narrow body TSSOP 16 pin package.

Features

- Uses 25 MHz Fundamental Mode Parallel Resonant Crystal
- External Loop Filter is Not Required
- HCSL Differential Output or LVDS with Proper Termination
- Four Selectable Multipliers of the Input Frequency
- Output Enable with Tri-State Outputs
- PCIe Gen1, Gen2, Gen3, Gen4, QPI, UPI Jitter Compliant
- Phase Noise: @ 100 MHz

Offset Noise Power 100 Hz -109.4 dBc 1 kHz -127.8 dBc -136.2 dBc 10 kHz 100 kHz -138.8 dBc 1 MHz -138.2 dBc 10 MHz -161.4 dBc -163.00 dBc 20 MHz

- Typical Period Jitter RMS of 1.5 ps
- Operating Range 3.3 V ±10%
- Industrial Temperature Range -40°C to +85°C
- These are Pb-Free Devices



A = Assembly Location

L = Wafer Lot Y = Year W = Work Week • = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 6 of this data sheet.

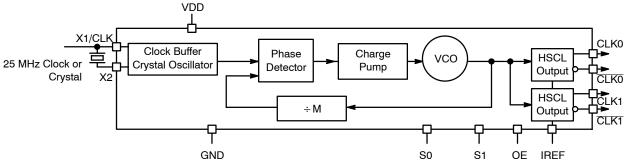


Figure 1. NB3N5573 Simplified Logic Diagram

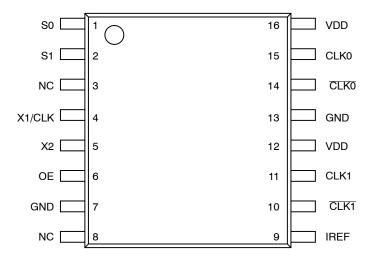


Figure 2. Pin Configuration (Top View)

Table 1. PIN DESCRIPTION

Pin Symbol I/O			Description			
1	S0	Input	LVTTL/LVCMOS frequency select input 0. Internal pullup resistor to V_{DD} . See output select table 2 for details.			
2	S1	Input	LVTTL/LVCMOS frequency select input 1. Internal pullup resistor to V_{DD} . See output select Table 2 for details.			
12, 16	V_{DD}	Power Supply	Positive supply voltage pins are connected to +3.3 V supply voltage.			
4	X1/CLK	Input	Crystal or Clock input. Connect to 25 MHz crystal source or single-ended clock.			
5	X2	Input	Crystal input. Connect to a 25 MHz crystal or leave unconnected for clock input.			
6	OE	Input	Output enable tri-states output when connected to GND. Internal pullup resistor to V _{DD} .			
7, 13	GND Power Supply		Ground 0 V. These pins provide GND return path for the devices.			
9	I _{REF}	Output	Output current reference pin. Precision resistor (typ. 475 Ω) is connected to set the output current.			
11	CLK1	HCSL or LVDS Output	Noninverted clock output. (For LVDS levels see Figure 4)			
10	CLK1	HCSL or LVDS Output	Inverted clock output. (For LVDS levels see Figure 4)			
15	CLK0	HCSL or LVDS Output	Noninverted clock output. (For LVDS levels see Figure 4)			
14	CLK0	HCSL or LVDS Output	Inverted clock output. (For LVDS levels see Figure 4)			
3, 8	NC		Do not connect			

Table 2. OUTPUT FREQUENCY SELECT TABLE WITH 25MHz CRYSTAL

S1*	S0*	CLK Multiplier	f _{CLKout} (MHz)
L	L	1x	25
L	Н	4x	100
Н	L	5x	125
Н	Н	8x	200

^{*}Pins S1 and S0 default high when left open.

Recommended Crystal Parameters

Crystal	Fundamental AT–Cut
Frequency	25 MHz
Load Capacitance	16-20 pF
Shunt Capacitance, C0	7 pF Max
Equivalent Series Resistance	50 Ω Max
Initial Accuracy at 25 °C	±20 ppm
Temperature Stability	±30 ppm
Aging	±20 ppm
Drive Level	100 μW Max

Table 3. ATTRIBUTES

Characte	Value			
ESD Protection	Human Body Model	> 2 kV		
RPU - OE, S0 and S1 Pull-up Re	RPU - OE, S0 and S1 Pull-up Resistor			
Moisture Sensitivity, Indefinite Tim	Moisture Sensitivity, Indefinite Time Out of Dry Pack (Note 1)			
Flammability Rating	Oxygen Index: 28 to 34	UL 94 V-0 @ 0.125 in		
Transistor Count	7623			
Meets or exceeds JEDEC Spec E				

^{1.} For additional information, see Application Note AND8003/D.

Table 4. MAXIMUM RATINGS (Note 2)

Symbol	Parameter	Condition 1	Condition 2	Rating	Unit
V_{DD}	Positive Power Supply	GND = 0 V		4.6	V
VI	Input Voltage (V _{IN})	GND = 0 V	$GND \leq V_I \leq V_{DD}$	-0.5 V to V _{DD} +0.5 V	V
T _A	Operating Temperature Range			-40 to +85	°C
T _{stg}	Storage Temperature Range			-65 to +150	°C
θ_{JA}	Thermal Resistance (Junction-to-Ambient)	0 lfpm 500 lfpm	TSSOP-16 TSSOP-16	138 108	°C/W °C/W
θЈС	Thermal Resistance (Junction-to-Case)	(Note 3)	TSSOP-16	33 to 36	°C/W
T _{sol}	Wave Solder			265	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

Table 5. DC CHARACTERISTICS (V_{DD} = $3.3~V\pm10\%$, GND = 0~V, T_A = $-40^{\circ}C$ to $+85^{\circ}C$, Note 4)

Symbol	Characteristic	Min	Тур	Max	Unit
VDD	Power Supply Voltage	2.97	3.3	3.63	V
I _{DD}	Power Supply Current		120	135	mA
I _{DDOE}	Power Supply Current when OE is Set Low			65	mA
V _{IH}	Input HIGH Voltage (X/CLK, S0, S1, and OE)	2000		V _{DD} + 300	mV
V _{IL}	Input LOW Voltage (X/CLK, S0, S1, and OE)	GND - 300		800	mV
V _{OH}	Output HIGH Voltage for HCSL Output (See Figure 5)	660	700	850	mV
V _{OL}	Output LOW Voltage for HCSL Output (See Figure 5)	-150	0	150	mV
V _{cross}	Crossing Voltage Magnitude (Absolute) for HCSL Output	250		550	mV
ΔV_{cross}	Change in Magnitude of V _{cross} for HCSL Output			150	mV

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm.

Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and not valid simultaneously. If stress limits are exceeded device functional operation is not implied, damage may occur and reliability may be affected.

^{3.} JEDEC standard multilayer board – 2S2P (2 signal, 2 power).

^{4.} Measurement taken with outputs terminated with R_S = 33.2 Ω , R_L = 49.9 Ω , with test load capacitance of 2 pF and current biasing resistor set at 475 Ω . See Figure 3.

Table 6. AC CHARACTERISTICS (V_{DD} = $3.3~V \pm 10\%$, GND = 0~V, $T_A = -40^{\circ}C$ to $+85^{\circ}C$; Note 5)

Symbol	Characteristic	Min	Тур	Max	Unit
f _{CLKIN}	Clock/Crystal Input Frequency		25		MHz
f _{CLKOUT}	Output Clock Frequency	25		200	MHz
θ_{NOISE}	Phase–Noise Performance f _{CLKx} = 200 MHz/100 MHz				dBc/Hz
	@ 100 Hz offset from carrier		-103/-109		
	@ 1 kHz offset from carrier		-118/-127.8		1
	@ 10 kHz offset from carrier		-122/-136.2		1
	@ 100 kHz offset from carrier		-130/-138.8		1
	@ 1 MHz offset from carrier		-132/-138.2		1
	@ 10 MHz offset from carrier		-149/-164		1
t _{JITTER}	Period Jitter Peak-to-Peak (Note 6) f _{CLKx} = 200 MHz		10	20	ps
	Period Jitter RMS (Note 6) f _{CLKx} = 200 MHz		1.5	3	
	Cycle-Cycle RMS Jitter (Note 7) f _{CLKx} = 200 MHz		2	5	
	Cycle-to-Cycle Peak to Peak Jitter (Note 7) f _{CLKx} = 200 MHz		20	35	ps
$t_{JIT(\Phi)}$	Additive Phase RMS Jitter, Integration Range 12 kHz to 20 MHz		0.4		ps
OE	Output Enable/Disable Time		10		μs
tDUTY_CYCLE	Output Clock Duty Cycle (Measured at cross point)	45	50	55	%
t _R	Output Risetime (Measured from 175 mV to 525 mV, Figure 5)	175	340	700	ps
t _F	Output Falltime (Measured from 525 mV to 175 mV, Figure 5)	175	340	700	ps
Δt_R	Output Risetime Variation (Single-Ended)			125	ps
Δt_{F}	Output Falltime Variation (Single-Ended)			125	ps
Stabilization Time	Stabilization Time From Powerup V _{DD} = 3.3 V		3.0		ms

NOTE: Device will meet the specifications after thermal equilibrium has been established when mounted in a test socket or printed circuit board with maintained transverse airflow greater than 500 lfpm.

^{5.} Measurement taken from differential output on single–ended channel terminated with R_S = 33.2 Ω, R_L = 49.9 Ω, with test load capacitance of 2 pF and current biasing resistor set at 475 Ω. See Figure 3.
6. Sampled with 10000 cycles.
7. Sampled with 1000 cycles.

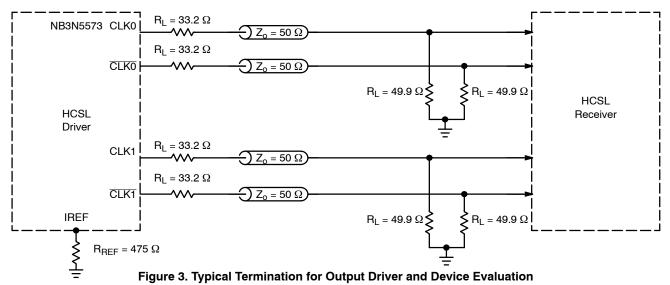
Table 7. ELECTRICAL CHARACTERISTICS - PHASE JITTER PARAMETERS

Symbol	Parameter	Conditions (Notes 8 and 9)	Min	Тур	Max	Industry Limit	Unit
t _{jphPCleG1}		PCle Gen 1 (Notes 10 and 11)		10	16	86	ps (p-p)
		PCIe Gen 2 Lo Band 10 kHz < f < 1.5 MHz (Note 10)		0.2	0.25	3	ps (rms)
^t jphPCleG2		PCIe Gen 2 High Band 1.5 MHz < f < Nyquist (50 MHz) (Note 10)		0.9	1.2	3.1	ps (rms)
t _{jphPCle} G3		PCIe Gen 3 (PLL BW of 2–4 MHz, CDR = 10 MHz) (Note 10)		0.2	0.3	1	ps (rms)
t _{jphPCleG4}	RMS Phase Jitter	PCIe Gen 4 (PLL BW of 2–4 MHz, CDR = 10 MHz) (Note 10)		0.21	0.3	0.5	ps (rms)
t _{jphUPI}		UPI (9.6 Gb/s, 10.4 Gb/s or 11.2 Gb/s, 100 MHz, 12 UI)		0.62	0.7	1.0	ps (rms)
		QPI & SMI (100.00 MHz or 133.33 MHz, 4.8 Gb/s, 6.4 Gb/s 12UI) (Note 12)		0.1	0.3	0.5	ps (rms)
t _{jphQPI} SMI		QPI & SMI (100.00 MHz, 8.0 Gb/s, 12UI) (Note 12)		0.1	0.15	0.3	ps (rms)
		QPI & SMI (100.00 MHz, 9.6 Gb/s, 12UI) (Note 12)		0.07	0.1	0.2	ps (rms)

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- 9. Guaranteed by design and characterization, not tested in production
- 10. See http://www.pcisig.com for complete specs
- 11. Sample size of at least 100K cycles. This figures extrapolates to 108 ps pk-pk @ 1M cycles for a BER of 1-12.
- 12. Calculated from Intel-supplied Clock Jitter Tool v 1.6.3.

HCSL INTERFACE



^{8.} Applies to all outputs.

LVDS COMPATIBLE INTERFACE

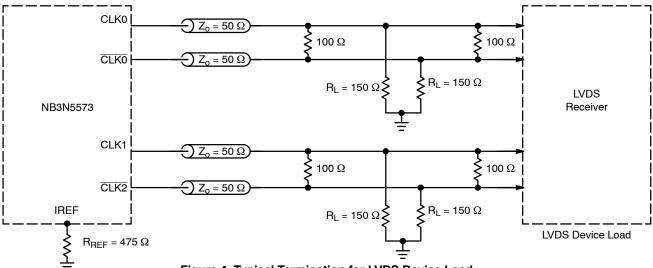


Figure 4. Typical Termination for LVDS Device Load

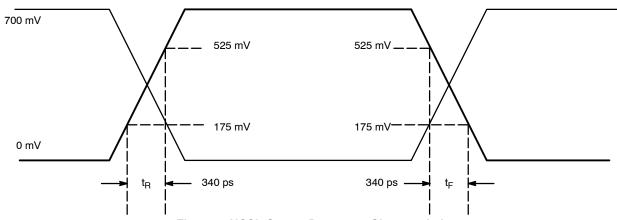


Figure 5. HCSL Output Parameter Characteristics

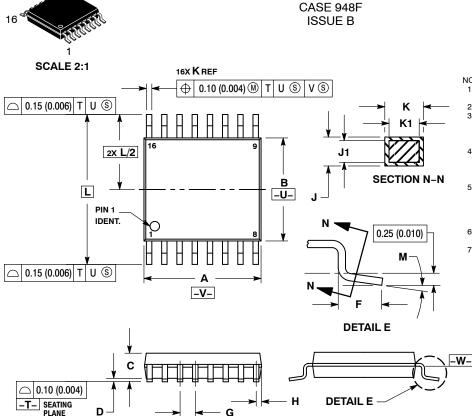
ORDERING INFORMATION

Device	Package	Shipping [†]
NB3N5573DTG	TSSOP-16 (Pb-Free)	96 Units / Rail
NB3N5573DTR2G	TSSOP-16 (Pb-Free)	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



DATE 19 OCT 2006



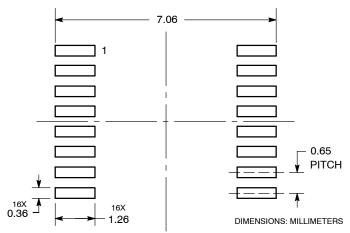
TSSOP-16 WB

NOTES

- DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A DOES NOT INCLUDE MOLD FLASH. PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT
- EXCEED 0.15 (0.006) PER SIDE.
 DIMENSION B DOES NOT INCLUDE
 INTERLEAD FLASH OR PROTRUSION.
- INTERLEAD FLASH OR PROTRUSION.
 INTERLEAD FLASH OR PROTRUSION SHALL
 NOT EXCEED 0.25 (0.010) PER SIDE.
 DIMENSION K DOES NOT INCLUDE DAMBAR
 PROTRUSION. ALLOWABILE DAMBAR
 PROTRUSION SHALL BE 0.08 (0.003) TOTAL
 IN EXCESS OF THE K DIMENSION AT
 MAXIMUM MATERIAL CONDITION.
 TERMINIAL NILMBERS ADE SUCIUMI ECIP.
- TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
- DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.90	5.10	0.193	0.200
В	4.30	4.50	0.169	0.177
С		1.20		0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65	BSC	0.026	BSC
Н	0.18	0.28	0.007	0.011
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40	6.40 BSC		BSC
M	0 °	8°	0 °	8 °

RECOMMENDED SOLDERING FOOTPRINT*



^{*}For additional information on our Pb-Free strategy and soldering details, please download the onsemi Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*



= Specific Device Code XXXX Α = Assembly Location

= Wafer Lot L = Year W = Work Week G or • = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	98ASH70247A	Electronic versions are uncontrolled except when accessed directly from the Document Rep Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.			
DESCRIPTION:	TSSOP-16		PAGE 1 OF 1		

onsemi and ONSEMI are trademarks of Semiconductor Components Industries, LLC dba onsemi or its subsidiaries in the United States and/or other countries. onsemi reserves the right to make changes without further notice to any products herein. onsemi makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. onsemi does not convey any license under its patent rights nor the rights of others.

onsemi, Onsemi, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. Onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using onsemi products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by onsemi. "Typical" parameters which may be provided in onsemi data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. onsemi does not convey any license under any of its intellectual property rights nor the rights of others. onsemi products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA class 3 medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase

ADDITIONAL INFORMATION

TECHNICAL PUBLICATIONS:

 $\textbf{Technical Library:} \ \underline{www.onsemi.com/design/resources/technical-documentation}$

onsemi Website: www.onsemi.com

ONLINE SUPPORT: www.onsemi.com/support

For additional information, please contact your local Sales Representative at

www.onsemi.com/support/sales